

Notice of References CitedApplication/Control
09/716,415Applicant(s)/Patent Under
Reexamination
TAKEDA ET AL.Examiner
Hai V. NguyenArt Unit
2142

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2001/0017712	08-2001	Kasatani, Kiyoshi	358/1.15
	B	US-6,622,266	09-2003	Goddard et al.	714/44
	C	US-6,618,749	09-2003	Saito et al.	709/207
	D	US-6,587,219	07-2003	Saito et al.	358/1.15
	E	US-6,522,421	02-2003	Chapman et al.	358/1.15
	F	US-6,519,048	02-2003	Tanaka, Tetsuo	358/1.13
	G	US-6,512,593	01-2003	Yashiki, Satoshi	358/1.15
	H	US-6,470,332	10-2002	Weschler, Paul	707/3
	I	US-6,307,643	10-2001	Okada et al.	358/1.15
	J	US-6,223,226	04-2001	Miyahara, Koji	709/241
	K	US-6,157,706	12-2000	Rachelson, Tevya A.	379/100.08
	L	US-5,832,208	11-1998	Chen et al.	713/201
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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